

**In the Specification**

Please amend the Abstract of the disclosure by inserting the underlined text ("\_\_\_\_") and removing the stricken text ("—").

A device testing system ~~comprising that has~~ automated test equipment (ATE), ~~which~~ configured to interfaces to a device under test (DUT). ~~The device testing system and logic~~ configured to selects a test set of data comprising a plurality of test pairs, ~~the test pairs~~ indicative of DUT parameter values. ~~The system, the logic further~~ configured to selects a subset of the plurality of test pairs from the test set of data ~~and to tests~~ the DUT via the ATE with a portion of the selected subset based upon the test results of at least one of the test pairs.